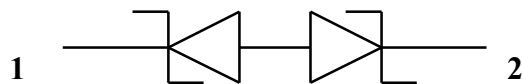
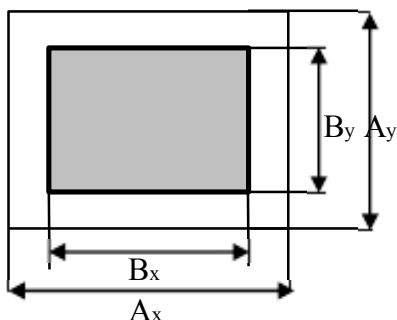


SMB-05L21, SMB-05L22, SMB-05L23

Chip Bi - directional TVS diode in wafer form, 4 inch.



Mechanical data: $A_x=430\mu\text{m}$, $A_y=380\mu\text{m}$.

$B_x=230\mu\text{m}$, $B_y=180\mu\text{m}$

Chip thickness: a) $138\pm 12\mu\text{m}$ – for SMB-05L21;
 b) $230\pm 20\mu\text{m}$ – for SMB-05L22;
 c) $470\pm 20\mu\text{m}$ – for SMB-05L23.

Scribe Line width - $60\mu\text{m}$.

Top Metal: Al - for wire bonding, $d=2.2\pm 0.2\mu\text{m}$.

Back side: a) Ti-Ni-Ag for soldering –for SMB-05L21, SMB-05L22.
 b) without metallization – for SMB-05L23.

Top Side - pin 1, **Back Side** - pin 2.

Probing: a) **sampling testing:** no bad dice inking;
 guaranteed good dice quantity $\geq 95\%$.

b) **100% testing (if agreed with customer):** wafer mapping data;
 no bad dice inking.

Schematic and pinning diagram.

Limiting values

Parameter	Symbol	Conditions	Value	Unit
Reverse Stand-off voltage	V_{RWM}	-	5	V
Peak Pulse Power	P_{pp}	$t_p=8/20\mu\text{s}$	130*	W
Peak Pulse Current	I_{pp}	$t_p=8/20\mu\text{s}$	12*	A
Electrostatic Discharge	V_{ESD}	IEC 61000-4-2, level 4.	+/-8 (Contact); +/-15 (Air).	kV
Max.junction temperature	T_j	-	+150	°C

Characteristics ($T_j=25^\circ\text{C}$)

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V_{BR}	Breakdown voltage. Pin 1 to 2.	$I_R=1\text{mA}$	5.6	-	9.4	V
I_R	Reverse leakage current.	$V=\pm 5\text{V}$	-	-	90	nA
V_{CL}	Clamping Voltage	$I_{pp}=1\text{A}$, $t_p=8/20\mu\text{s}$ $I_{pp}=12\text{A}$, $t_p=8/20\mu\text{s}$	-	-	10* 14*	V
C_j	Diode capacitance. Pin 1 to 2.	$V_R=0\text{V}$, $f=1\text{MHz}$	-	24	30	pF

* For Device testing.